

Notice of References Cited

Application/Control No.

09/882,062

Applicant(s)/Patent Under Reexam

Emrick

Examiner

B. William Baumeister

Art Unit

2815

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	Document Number Country Code-Number-Kind Code	Date MM-YYYY ¹	Name	Classification ²	
A	5,478,653	12/1995	Guenzer	428	446
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N	52-89070	7/1977	Japan	Serizawa et al.	H01L	21/20
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NON-PATENT DOCUMENTS

	Include, as applicable: Author, Title, Date, Publisher, Edition or Volume, Pertinent Pages
U	Kaushik et al., "Device Characteristics of Crystalline Epitaxial Oxides on Silicon;" Device Research Conference, 2000, Conference Digest 58th DRC, pp. 17-20, June 19-21, 2000.
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^{*} A copy of this reference is not being furnished with this Office action. See MPEP § 707.05(a).¹ Dates in MM-YYYY format are publication dates.² Classifications may be U.S. or foreign.